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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

APPLICANT

Khader S. Abdel-Hafez et al

FILING DATE

January 23, 2004

GROUP

2857

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>R50</i>	US 2002/0188903 A1	12/2002	Chu et al	714	738	
<i>R50</i>	US 2003/0115521 A1	06/2003	Rajski et al	714	724	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>R50</i>	Ghosh-Dastidar et al, "A Rapid and Scalable Diagnosis Scheme for BIST Environments with a Large Number of Scan Chains", Proc., IEEE VLSI Test Symposium (VTS), pp. 79-85, 2000.

EXAMINER

R. Stephen Doherty

DATE CONSIDERED

November 14, 2005

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.